



Verification Environment for ALTIROC3 ASIC of the ATLAS High Granularity Timing Detector

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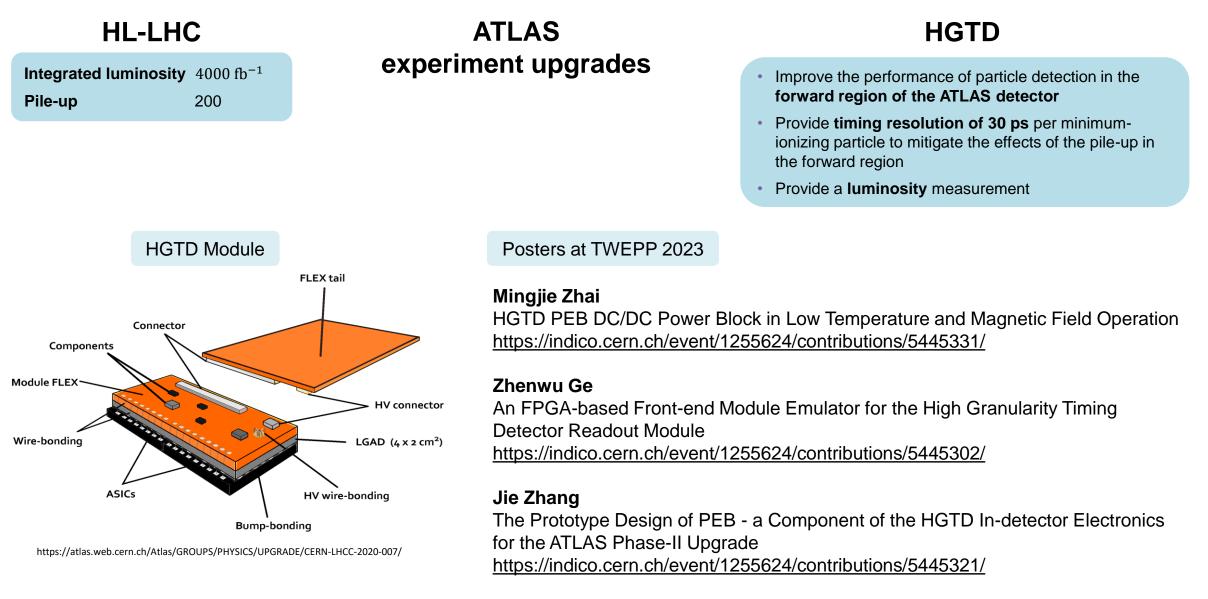
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High Granularity Timing Detector for HL-LHC







ALTIROC3 requirements and specifications

Main projects challenges from a verification point of view:

- Source code management and IP-blocks versioning
- Complex clock architecture with several domains
- Accurate analog IP-blocks models using digital-on-top design methodology
- More than **1000 configurable registers**
- SEE simulations



ALTIROC3 requirements and specifications

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Examples of verification methodologies adopted



Chip area 22.5 mm x 20 mm Number of pixels 15 x 15 = 225 Pixel size 1.3 mm x 1.3 mm Technology 130 nm technology

Minimum detectable charge	2 fC
TOA measurement	resolution 20 ps, range 2.5 ns
TOT measurement	resolution 40 ps, range 20 ns
Luminosity	resolution 100 ps, range 25 ns

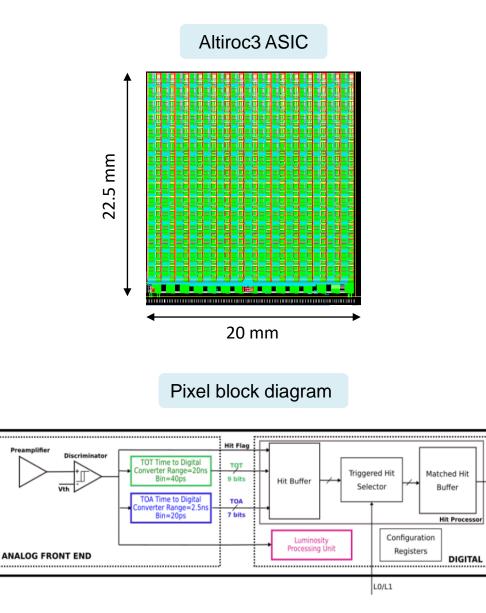
Triggered readout

- configurable transmission rate (320 Mbps, 640 Mbps, 1280 Mbps)
- configurable protocol (8b10b encoding, raw data)

Continuous readout

- fixed transmission rate 640 Mbps
- fixed protocol
 6b8b encoding

Power consumption	1.2 W (50% digital, 50% analog)
Radiation tolerance	TID 200 Mrad, SEE robustness





Main requirements:

- Same tools in the four different institutions
- IP-blocks, RTL, scripts version control

Each member of the team must be able to:

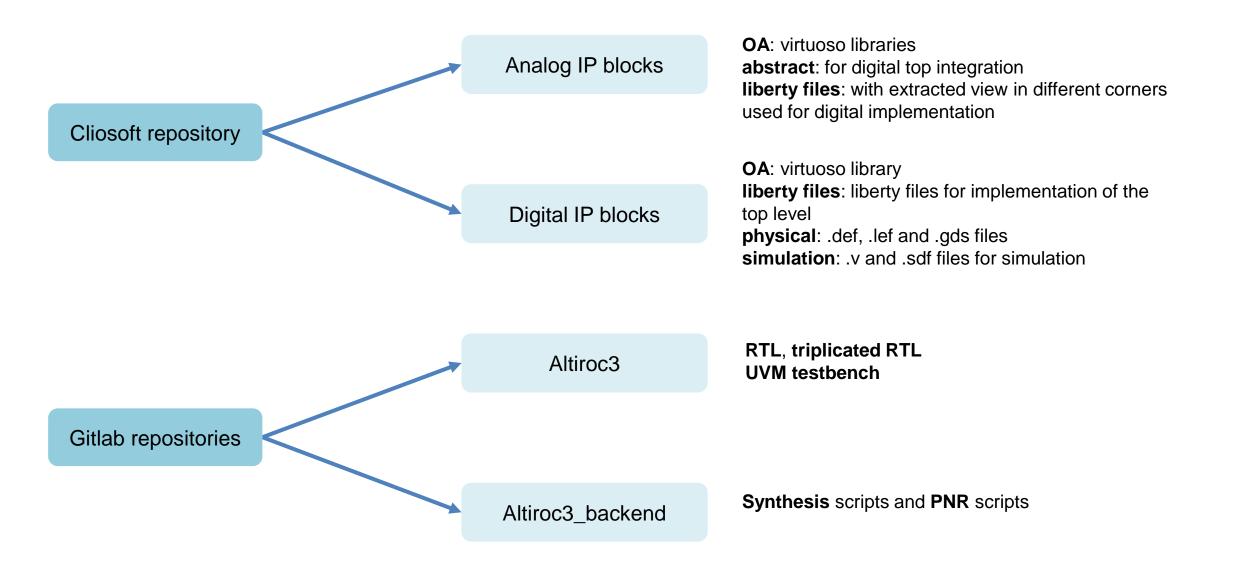
- Launch PNR flows
- Launch full chip simulations

Advantages:

- Easier collaboration
- Reproducibility of results

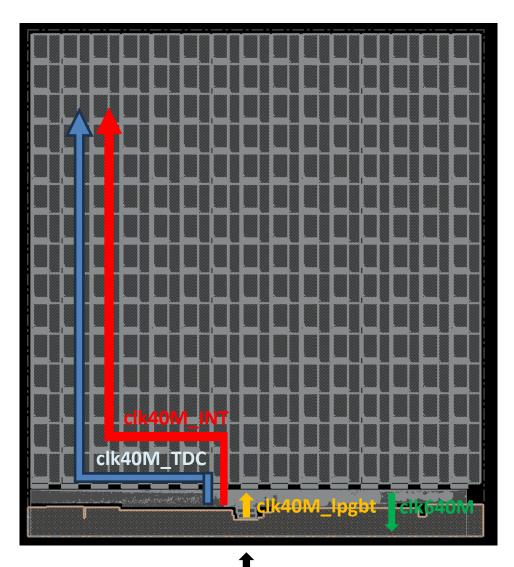
Multi-site project code organization





Altiroc3 simplified clock architecture





clk320M lpgbt

clk320M_lpgbt:

Input clock from LpGBT at 320 MHz

clk40M_lpgbt:

- Derived from clk320M_lpgbt
- Used to send out data always in phase

clk40M_INT for digital processing logic (matrix and periphery):

- Derived from clk320M_lpgbt
- 40 MHz clock, fully triplicated
- Skew maximized to spread current peaks over a larger period, minimizing noise
- Phase set according to clk40M_TDC rising edge to avoid digital current spikes affecting TDC measurement (ensuring always a distance among the two)

clk40M_TDC (stop condition for TDC):

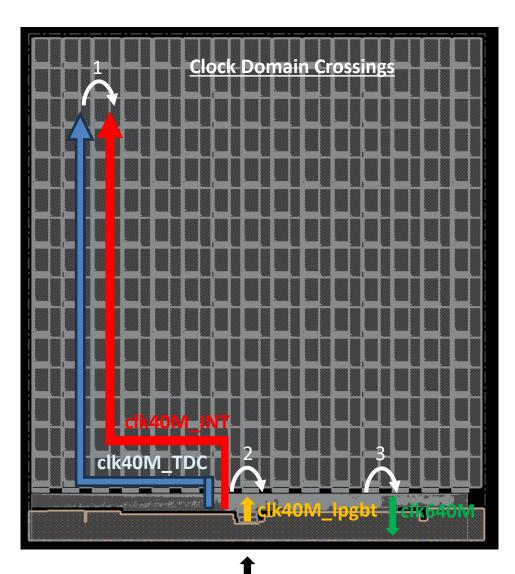
- 40 MHz clock, not triplicated
- Requires to be aligned with the Bunch Crossing (BC) collision for a TOA measurement with a range of 2.5 ns
- Very precise skew over all matrix (+- 150 ps)
- PLL minimizes jitter
- Coarse shift by 1.56 ns (range 25 ns)
- Fine shift by 100 ps (range 1.56 ns) with Phase Shifter

clk640M:

- Derived by the PLL
- Needed for high-frequency output serializers

Altiroc3 Clock Domain Crossings (CDC)





Clock Domain Crossings (CDC):

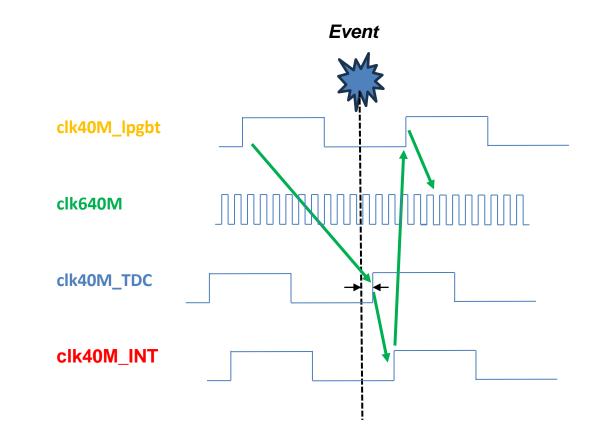
- 1. clk40M_TDC clk40M_INT in each pixel:
 - Data from TDC are sampled with clk40M_TDC and are transmitted to clk40M_INT domain for processing
 - clk40M_TDC and clk40M_int accumulate different delay along the column/matrix, the CDC is checked via Static Timing Analysis (STA) and exact delay is known for all pixels in all corners
- 2. clk40M_INT clk40M_lpgbt in periphery:
 - Data processed in the clk40M_INT domain must be aligned with clk40M_lpgbt domain for output transmission
 - Phase between them is known, custom CDC is used (different sampling edge positive/negative)

3. clk40M_lpgbt - clk640M

• CDC through a PLL

Example of data processing





- 1. clk40M_lpgbt is in the same domain of clk320M_lpgbt, received by the ASIC
- 2. clk40M_TDC is set according to Time Of Flight and position of ASIC in the detector, to align within 2.5 ns window around event
- 3. clk40M_INT is set to ensure a certain distance from clk40M_TDC where digital noise on TDC is minimized
- 4. clk640M transmits out the data

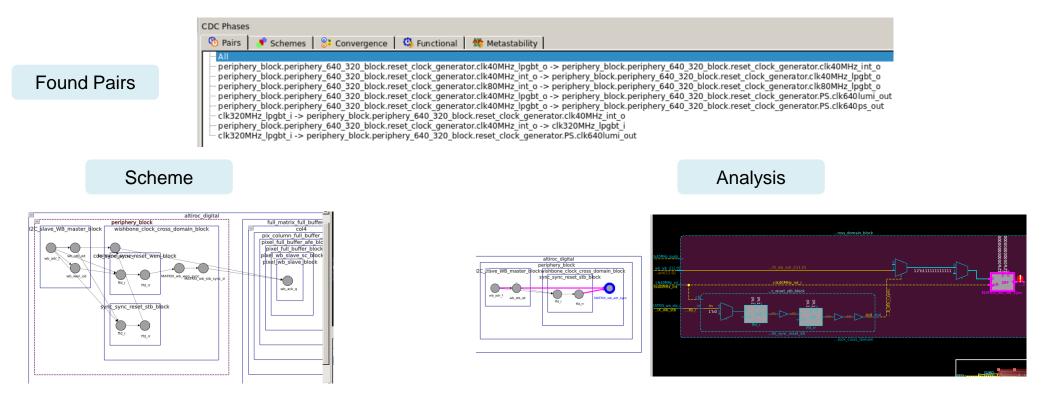
Verification of CDC with Formal Verification (JasperGold)



Efficiently identify all CDC at an early stage of the design (RTL level)

Debug structural failures (missing synchronizers, structural glitches, convergence/divergence)

Generate **assertions** for running protocol checks during functional verification (e.g.: data stable for N clock cycles, etc)

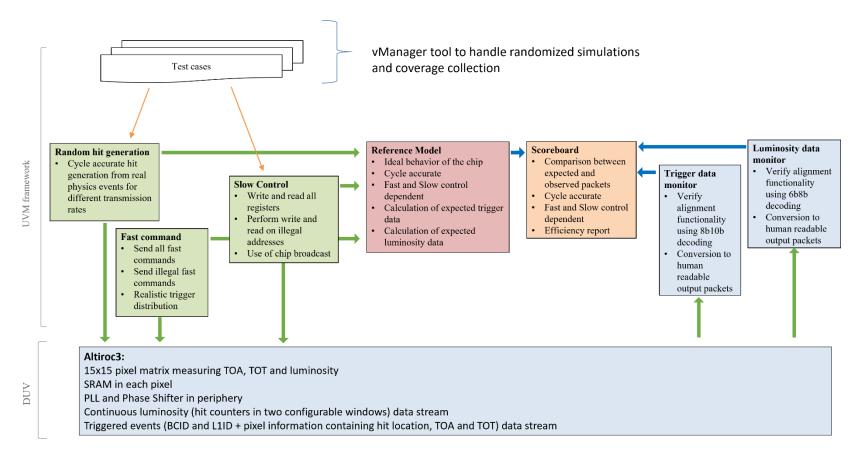


Limitation: only checks for structural errors, we still require functional verification

Verification of CDC with Functional Verification



Only possible when the design is already at an advanced stage (NETLIST level)



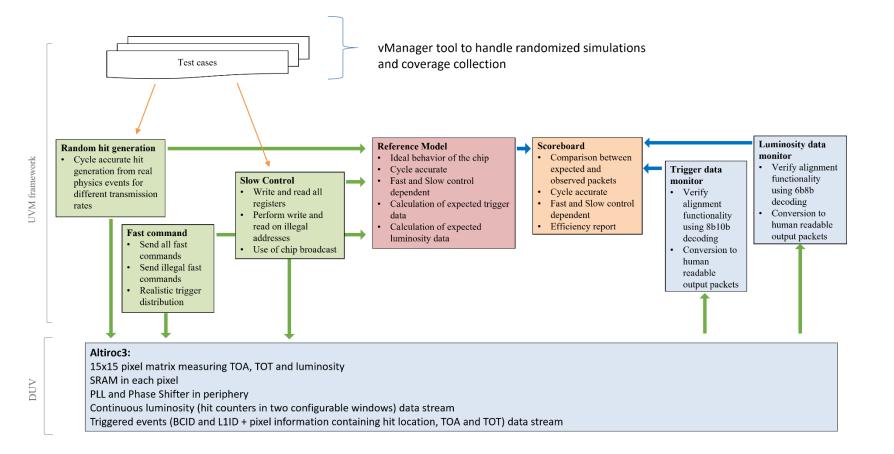
Ideally, one should develop the **UVM testbench** having in mind target application:

- Stimuli: Ability to move hit generation
- Randomization: Ability to configure internal clock phases in a 'constrained randomized' way
- Correctness: ASIC can proper sample hits and process data

Verification of CDC with Functional Verification



Only possible when the design is already at an advanced stage (NETLIST level)



Requires accurate Verilog models:

- Analog Front-End
- PLL
- Phase Shifter

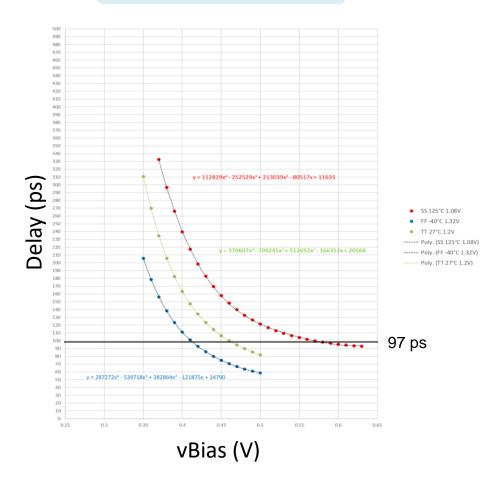
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Analog simulations with extracted view

Delay of a single delay cell

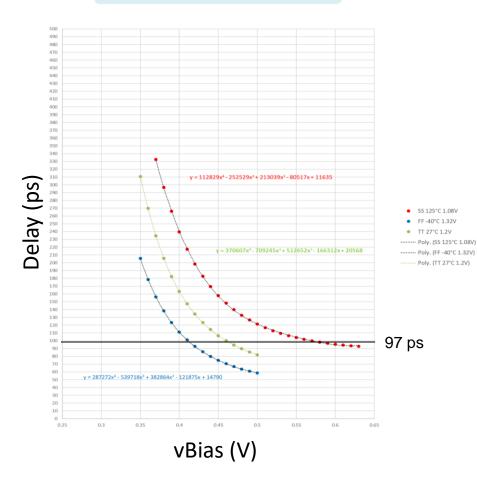


Phase Shifter Verilog model



Extraction of the model from Virtuoso and modifications of key blocks

Delay of a single delay cell



Example: Verilog model of a delay cell

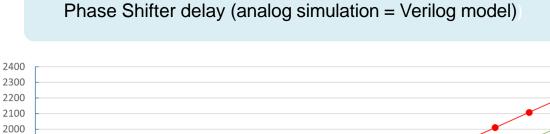
module delayCellBias (
output reg [31:0] biasp, input [31:0] biasn // in nano Volts	
);	
);	
//	//
// Compute the cell delay	
//	
// One should find the transfer function between the delay of a cell and the biasn (in a	ll three corners)
localparam CO = (1.47900e+04 : 2.05680e+04 : 1.16350e+04);	
localparam C1 = (-1.21875e+05 : -1.66312e+05 : -8.05170e+04);	
localparam C2 = (3.82864e+05 : 5.12652e+05 : 2.13039e+05);	
localparam C3 = (-5.39718e+05 : -7.09245e+05 : -2.52529e+05);	
<pre>localparam C4 = (2.87272e+05 : 3.70607e+05 : 1.12829e+05);</pre>	
// The following parameter controls how different the replica delay lines will be from t	he master delay line
// The parameter should be within 0.95% (-5%) and 1.05 (+5%)	
<pre>localparam delayLineMismatchParameter = 1.00; // Must be a real</pre>	
real vControlReal;	
integer delayInteger;	
<pre>real delayReal = 1e-12;</pre>	
always @(biasn) begin	
<pre>// Convert the control voltage from real to integer and then to binary:</pre>	
vControlReal = biasn*1.0e-9; // in Volts	
// Compute the cell delay:	
<pre>delayReal = 1.0e-12*delayLineMismatchParameter*(C0 + vControlReal*(C1 + vControlReal</pre>	*(C2 + vControlReal*(C3 + vControlReal*C4)))); // cell delay in
// Make sure delay never becomes too smal or negative!	
if(delavReal < 0.01e-12)	
delayReal = 0.01e-12;	
// Convert the delay from real to integer and then to binary:	
· · · · · · · · · · · · · · · · · · ·	
delayInteger = delayReal/2.0e-15: // Convert to fs seconds and integer, divide by tw	o to have delav of half cell
<pre>delayInteger = delayReal/2.0e-15; // Convert to fs seconds and integer, divide by tw biasp = delayInteger;</pre>	no to have delay of half cell

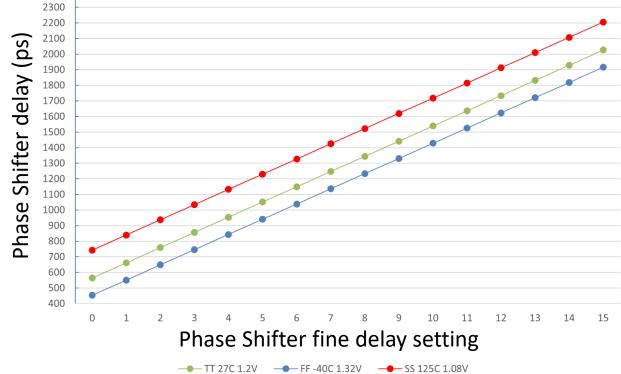
endmodule

Phase Shifter Verilog model



Phase Shifter behavior fully modeled in all corners





Constrained randomization:

- Moving the hit randomization with steps of 100 ps in a range of 25 ns (256 values)
- Constrain coarse delays and fine delays accordingly. For example, the phase for clk40M_TDC and clk40M_INT following the table:

CONF_CLKS_CTRL_CLK40_DELAY Table			
CLK40TDC_COARSE_DELAY[3:0]	CLK40_DELAY[6:4]		
0, 1	0		
2, 3	1		
4, 5	2		
6, 7	3		
8, 9	4		
10, 11	5		
12, 13	6		
14, 15	7		

Metrics:

		· · ·
🔺 🖺 altiroc_cfg_seq::luminosity_cfg_cov	68.75%	41 / 296 (13.85%)
	✓ 100%	2 / 2 (100%)
₽ cp_lumi_enable_clk	✓ 100%	2 / 2 (100%)
	✓ 100%	16 / 16 (100%)
🖺 cp_lumi_ps_clk40TDC_fine_delay	6.25%	1 / 16 (6.25%)
A×B cr_lumi_enable_cfg	✓ 100%	4 / 4 (100%)
A×B cr_lumi_phases_cfg	6.25%	16 / 256 (6.25%)
🔺 🖺 altiroc_cfg_seq::phases_cfg_cov	37.5%	33 / 288 (11.46%)
	✓ 100%	16 / 16 (100%)
🕒 cp_trigger_ps_clk40TDC_fine_delay	6.25%	1 / 16 (6.25%)
A×B cr_trigger_phases_cfg	6.25%	16 / 256 (6.25%)

Summary



Altiroc3 for ATLAS HGTD:

- 20 ps TOA meas. Resolution
- 40 ps TOT meas. resolution
- 100 ps luminosity meas. resolution

Main verification challenges and solutions:

- multi-site project -> efficient source code management and version control
- complex clock architecture -> increased complexity of verification environment
- critical analog macros
 -> development of accurate Verilog models

Two **complementary** approaches to verify CDC:

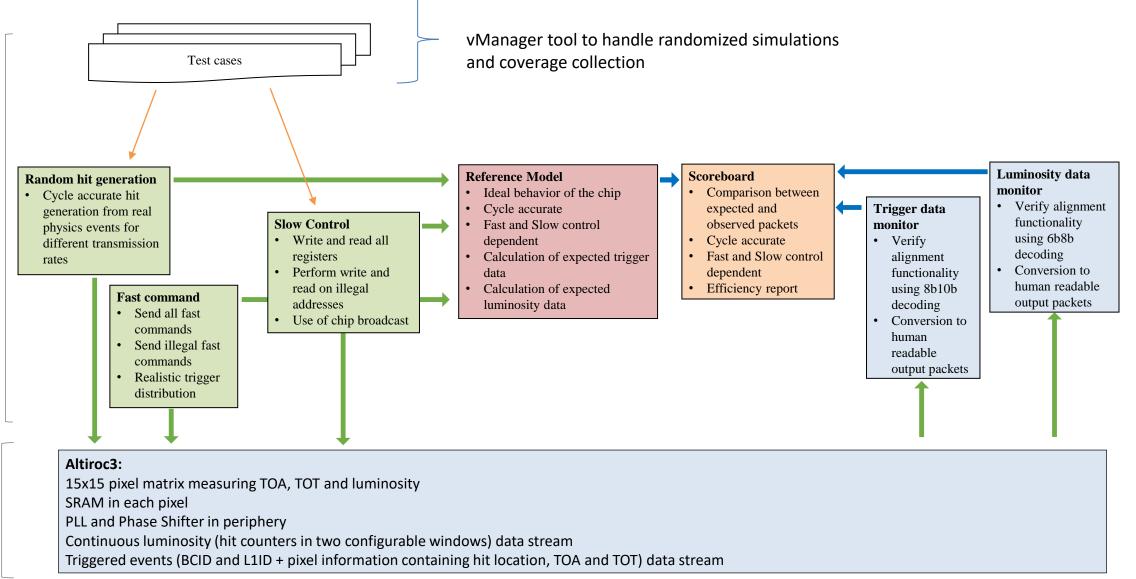
- formal verification using JasperGold tool
 -> fast results, early stage (RTL)
- functional verification using UVM framework -> NETLIST level, check correctness





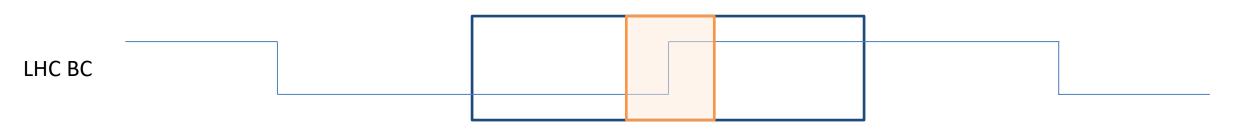
THANK YOU

UVM framework developed since September 2021



ATLAS





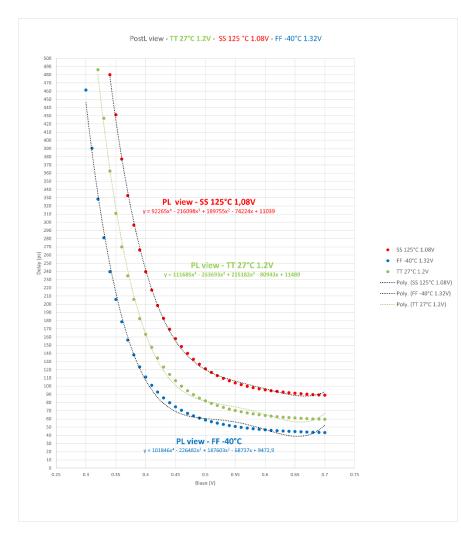
Hit injection over 12.5 ns:

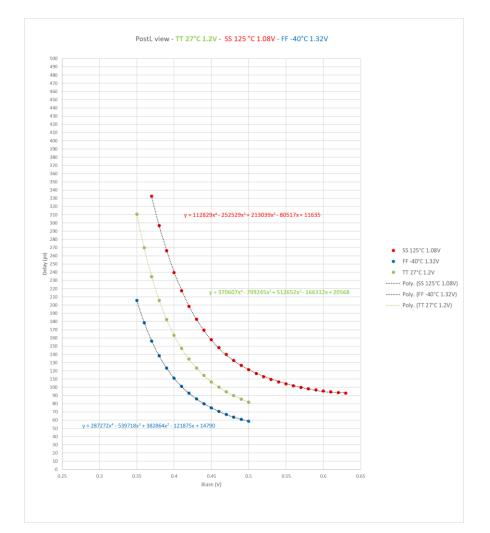
- Charges are injected around the BC posedge over 3.125 ns (number controlled with occupancy)
 - In reality the occupancy can go up to 35%: <u>https://aleopold.web.cern.ch/aleopold/hgtd/hgtd_asic_simul_hitdistros_log/</u>
- Few charges injected in the larger window of 12.5 ns to model afterglow effect (at maximum 5% of occupancy)

Phase Shifter Verilog model



Analog simulations to find relationship between voltage bias and delay in ps:







'The **SystemRDL** language, supported by the SPIRIT Consortium, was specifically designed to describe and implement a wide variety of <u>control status registers</u>. Using SystemRDL, developers can automatically **generate** and **synchronize** register views for specification, hardware design, software development, verification, and documentation.' (Wikipedia)

Example:

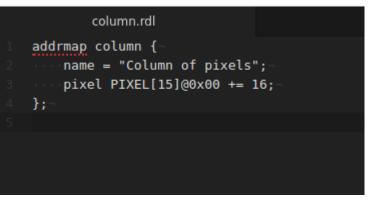
RDL files hierarchy



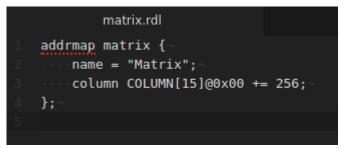
pixel.rdl

```
pixel.rdl
addrmap pixel {
   name = "Pixel";
   default regwidth = 8;
   default sw = rw;
   default hw = r;
   hdl_path = "q";
   reg {-
       hdl_path = "q";
       field {-
           desc = "Local agjustment of TOA LSB with slow delay line";
       } TOA LSB ADJ SLOW DL[3:0] = 4'b0000;
       field {-
           desc = "Local agjustment of TOA LSB with fast delay line";
       } TOA LSB ADJ FAST DL[7:4] = 4'b0000;
   } CONF_CTRL0 @ 0x0;
   reg {-
       hdl path = "q";
       field {-
           desc = "Local agjustment of TOT LSB";
       } TOT_LSB_ADJ[3:0] = 4'b0000;
       field {-
           desc = "'0': TOA TDC under reset";
       } TOA_TDC_CTRL[4:4] = 1;
       field {
           desc = "'0': TOT TDC under reset";
       } TOT_TDC_CTRL[5:5] = 1;
       field {-
           desc = "'0': Internal clock gated for SRAM";
       } SRAM_INT_GATING[6:6] = 1;
       field {
           desc = "'0': External clock gated for SRAM";
       } SRAM_EXT_GATING[7:7] = 1;
   } CONF_CTRL1 @ 0x1;
```

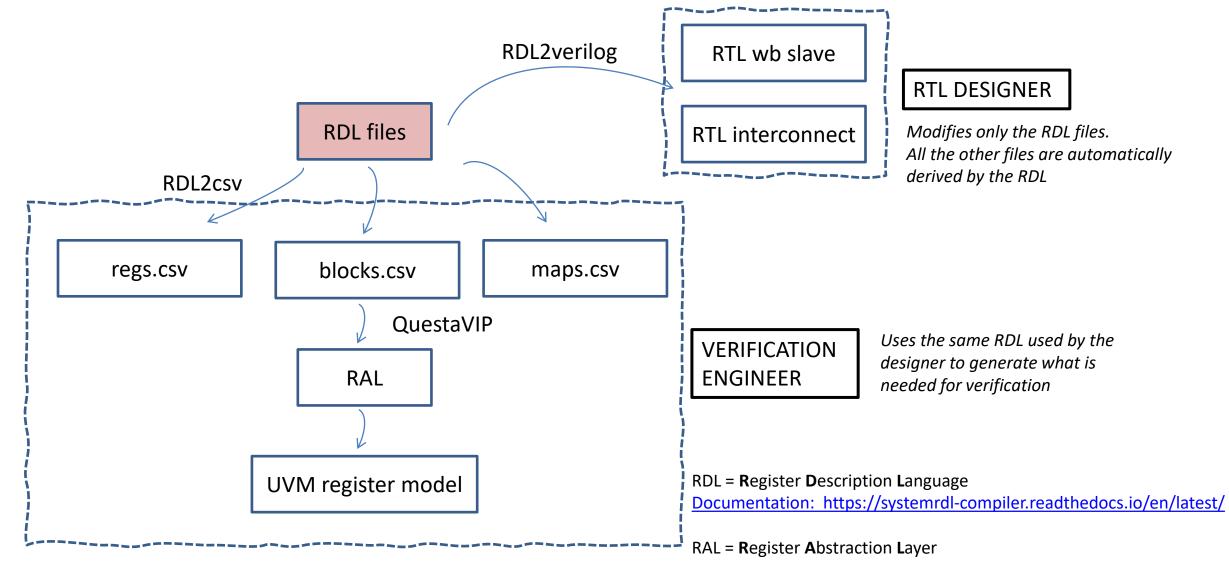
column.rdl



matrix.rdl







RTL TMR: SEU injection results

SEU verification strategy:

- I2C test case
- Running mode test case

I2C test case:

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• I2C operations never fail due to SEU and configuration is never lost in the ASIC

Running mode test case has four main categories:

- Triplicated registers -> No issues
- Untriplicated registers -> Reduced efficiency, but no synchronization issues
- Triplicated FIFOs -> No issues

 - Untripliated FIFOs -> Reduced efficiency, but no synchronization issues

We can still have issues in PNR due to low distance among registers or simplification SEU run only on digital part of the chip, not on analog blocks



